

Apı	plication/Control No.	Applicant(s)/Patent under Reexamination	
10/	768,345	SPILMAN ET AL	
Exa	aminer	Art Unit	
Tae	e H. Yoon	1714	

	SEAR	CHED	
Class	Subclass	Date	Examiner
524	507	9-18-06	%
	661		
428	661		
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INT	INTERFERENCE SEARCHED		
Class	Subclass	Date	Examiner
			1

SEARCH NOTES (INCLUDING SEARCH STRATEGY)				
	DATE	EXMR		
TAST Reviewed parest cases Inventor Search	9-9-66	w		